

Arria 10 DDR4 IP Parameterization

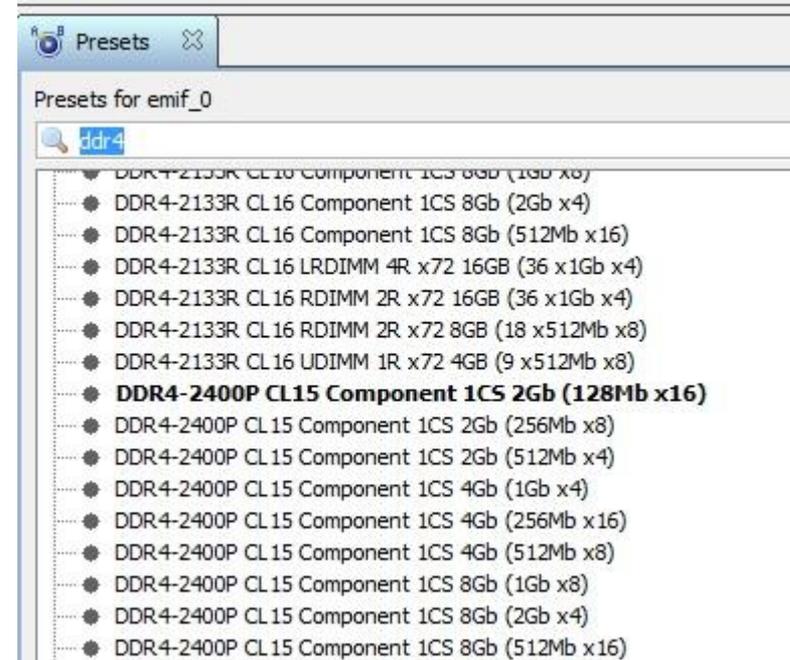
Selecting the DDR4 IP timing parameters from a Micron DDR4 device data sheet :

Memory Topology and Memory Timing tabs



Presets

- ◀ Based on JEDEC specifications
- ◀ Use as a starting point
 - Select a preset close to the requirement
 - ◀ Memory Format
 - Discrete Device
 - DIMM (UDIMM, RDIMM, LRDIMM)
 - ◀ Configuration
 - Maximum Throughput (DDR4-xxxx)
 - CAS latency
 - Rank/chip select
 - Capacity
 - Device Width
- ◀ Then modify as required
 - Some memory timing parameters may need to be changed



◀ DDR4 DIMMS

- To find the actual memory device used on the DIMM
 - ◀ Get the Base device part number from the DIMM datasheet

Table 3: Part Numbers and Timing Parameters – 4GB Modules

Base device: MT40A512M8,¹ 4Gb DDR4 SDRAM

Part Number ²	Module Density	Configuration	Mod Bandw
MTA8ATF51264AZ-2G3__	4GB	512 Meg x 64	19.2 G

Memory Timing 1

- Memory device **Speed bin** defines the maximum data rate that the memory device can support
 - Get from the DDR4 memory device part number **speed grade**

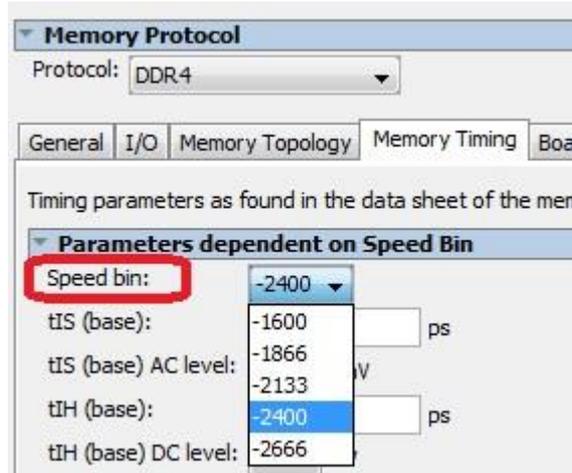


Table 1: Key Timing Parameters

Speed Grade	Data Rate (MT/s)
-083E ^{1, 2, 3, 4}	2400
-093F ^{1, 2, 3}	2133
-093E ^{1, 2}	2133
-107E ¹	1866

- Speed grade may have a letter suffix
 - Indicates CAS latency, tRCD, tRP

Memory Topology 1

Memory Topology -> Mode Register Settings : Latencies

-> Use Memory Device data sheet **Speed bin table**

– Take into account

- Memory speed grade
- DDR4 clock period tCK
- DBI

Data mask
 Write DBI
 Read DBI
 Enable ALERT#/PAR pins
 ALERT# pin placement: Automatically select a location

Mode Register Settings

Mode Register 0
 Burst Length: Fixed BLS
 Read Burst Type: Sequential
 Memory CAS latency setting: 15

Mode Register 1
 Output drive strength setting: 00 - RZQ/7
 Memory additive CAS latency setting: Disabled
 ODT Rtt nominal value: ODT Disabled

Mode Register 2
 Auto self-refresh method: Manual - Normal Temp. Range
 Memory write CAS latency setting: 12
 Dynamic ODT (Rtt_WR) value: RZQ/1

Table 139: DDR4-2400 Speed Bins and Operating Conditions

DDR4-2400 Speed Bin		-083F		-083E		-083		Unit
CL-nRCD-nRP		15-15-15		16-16-16		17-17-17		
Parameter	Symbol	Min	Max	Min	Max	Min	Max	
Internal READ command to first data	'AA	12.5	18.00	13.32	18.00	14.16	18.00	ns

READ: nonDBI	READ: DBI	WRITE	Symbol	Min	Max	Min	Max	Min	Max	Unit
CL = 9	CL = 11	CWL = 9	'tCK	1.5	1.6	1.5	1.6	Reserved		ns
CL = 10	CL = 12	CWL = 9	'tCK	1.5	1.6	Reserved		1.5	1.6	ns
CL = 10	CL = 12	CWL = 9, 11	'tCK	Reserved		Reserved		Reserved		ns
CL = 11	CL = 13	CWL = 9, 11	'tCK	Reserved		1.25	<1.5	1.25	<1.5	ns
CL = 12	CL = 14	CWL = 9, 11	'tCK	1.25	<1.5	1.25	<1.5	1.25	<1.5	ns
CL = 12	CL = 14	CWL = 10, 12	'tCK	Reserved		Reserved		Reserved		ns
CL = 13	CL = 15	CWL = 10, 12	'tCK	Reserved		1.071	<1.25	1.071	<1.25	ns
CL = 14	CL = 16	CWL = 10, 12	'tCK	1.071	<1.25	1.071	<1.25	1.071	<1.25	ns
CL = 14	CL = 17	CWL = 11, 14	'tCK	Reserved		Reserved		Reserved		ns
CL = 15	CL = 18	CWL = 11, 14	'tCK	Reserved		0.937 ⁶	<1.071	0.937	<1.071	ns
CL = 16	CL = 19	CWL = 11, 14	'tCK	0.937	<1.071	0.937	<1.071	0.937	<1.071	ns
CL = 15	CL = 18	CWL = 12, 16	'tCK	0.833	<0.937	Reserved		Reserved		ns
CL = 16	CL = 19	CWL = 12, 16	'tCK	0.833	<0.937	0.833	<0.937	Reserved		ns
CL = 17	CL = 20	CWL = 12, 16	'tCK	0.833	<0.937	0.833	<0.937	0.833	<0.937	ns
CL = 18	CL = 21	CWL = 12, 16	'tCK	0.833	<0.937	0.833	<0.937	0.833	<0.937	ns
Supported CL settings				9, 10, 12, 14-18		9, 11-18		10-18		nCK
Supported CL settings with read DBI				11, 12, 14, 16-21		13-16, 18-21		12-16, 18-21		nCK
Supported CWL settings				9, 10, 11, 12, 14, 16		9, 10, 11, 12, 14, 16		9, 10, 11, 12, 14, 16		nCK

Memory Timing 2

Presets are typically for the DDR4 device speed grade **clocked at its highest frequency**

Some parameters may need to be modified :

- Clocking at lower frequency
- Using an industrial temperature DDR4 device
 - ◀ Refresh rate tREFI -> 3.9us

The screenshot shows the 'Memory Timing' tab of a configuration tool. It displays a list of timing parameters for a DDR4 device, categorized into three sections: 'Parameters dependent on Speed Bin', 'Parameters dependent on Speed Bin, Operating Frequency, and Page Size', and 'Parameters dependent on Density and Temperature'. Each parameter is shown with its name, a numerical value, and its unit.

Parameter	Value	Unit
Speed bin:	-2400	
tIS (base):	60	ps
tIS (base) AC level:	100	mV
tIH (base):	95	ps
tIH (base) DC level:	75	mV
tdIWW_dj:	0.1	cycles
VdiWW_total:	136	mV
tDQSQ:	66	ps
tQH:	0.38	cycles
tDQSCK:	165	ps
tDQSS:	0.27	cycles
tQSH:	0.38	cycles
tDSH:	0.18	cycles
tDSS:	0.18	cycles
tWLS:	108.0	ps
tWLH:	108.0	ps
tINIT:	500	us
tMRD:	8	cycles
tRAS:	32.0	ns
tRCD:	12.5	ns
tRP:	12.5	ns
tWR:	15.0	ns

Parameter	Value	Unit
tRRD_S:	7	cycles
tRRD_L:	8	cycles
tFAW:	30.0	ns
tCCD_S:	4	cycles
tCCD_L:	6	cycles
tWTR_S:	3	cycles
tWTR_L:	9	cycles

Parameter	Value	Unit
tRFC:	160.0	ns
tREFI:	7.8	us

Memory Timing 3

- From the Electrical Characteristics and AC Timing Parameters table
 - Use the DDR4-xxxx column that the device is rated for
 - eg 1200MHz device -> use DDR4-2400
- From the Electrical Characteristics and AC Timing Parameters table
 - Use the DDR4-xxxx column that the device is rated for
 - Calculate values as required using :
 - Page size (0.5K, 1K or 2K)
 - Memory Clock Frequency (tCK)
- See next slide for data sheet extracts

Timing parameters as found in the data sheet of the memory device.

Parameters dependent on Speed Bin		
Speed bin:	-2400	
tIS (base):	60	ps
tIS (base) AC level:	100	mV
tIH (base):	95	ps
tIH (base) DC level:	75	mV
tdIVW_dj:	0.1	cycles
VdiVW_total:	136	mV
tDQSQ:	66	ps
tQH:	0.38	cycles
tDQSCK:	165	ps
tDQSS:	0.27	cycles
tQSH:	0.38	cycles
tDSH:	0.18	cycles
tDSS:	0.18	cycles
tWLS:	108.0	ps
tWLH:	108.0	ps
tINIT:	500	us
tMRD:	8	cycles
tRAS:	32.0	ns
tRCD:	12.5	ns
tRP:	12.5	ns
tWR:	15.0	ns
Parameters dependent on Speed Bin, Operating Frequency, and Page Size		
Update the following as you change the operating frequency, even if the device speed bin has not changed.		
tRRD_S:	7	cycles
tRRD_L:	8	cycles
tFAW:	30.0	ns
tCCD_S:	4	cycles
tCCD_L:	6	cycles
tWTR_S:	3	cycles
tWTR_L:	9	cycles
Parameters dependent on Density and Temperature		
Update the following as you change the physical memory device density. Incorrect values can cause data corruption.		
tRFC:	160.0	ns
tREFI:	7.8	us

Memory Timing 4

Extracts from a Micron Memory DDR4 Datasheet

Table 2: Addressing

Parameter	1024 Meg x 4	512 Meg x 8	256 Meg x 16
Number of bank groups	4	4	2
Bank group address	BG[1:0]	BG[1:0]	BG0
Bank count per group	4	4	4
Bank address in bank group	BA[1:0]	BA[1:0]	BA[1:0]
Row addressing	64K (A[15:0])	32K (A[14:0])	32K (A[14:0])
Column addressing	1K (A[9:0])	1K (A[9:0])	1K (A[9:0])
Page size ¹	512B / 1KB ²	1KB	2KB

Notes: 1. Page size is per bank, calculated as follows:
 Page size = $2^{\text{COLBITS}} \times \text{ORG}/8$, where COLBIT = the number of column address bits and ORG = the number of DQ bits.

Table 143: Electrical Characteristics and AC Timing Parameters (Continued)

Parameter	Symbol	DDR4-1600		DDR4-1866		DDR4-2133		DDR4-2400		Unit	
		Min	Max	Min	Max	Min	Max	Min	Max		
DLL locking time	^t DLLK	597	–	597	–	768	–	768	–	CK	
CMD, ADDR setup time to CK_t, CK_c referenced to V _{IH(AC)} and V _{IL(AC)} levels	Base	^t IS	115	–	100	–	80	–	62	–	ps
	V _{REFCA}	^t IS _{VREF}	215	–	200	–	180	–	162	–	ps
CMD, ADDR hold time to CK_t, CK_c referenced to V _{IH(DC)} and V _{IL(DC)} levels	Base	^t H	140	–	125	–	105	–	87	–	ps
	V _{REFCA}	^t H _{VREF}	215	–	200	–	180	–	162	–	ps
CTRL, ADDR pulse width for each input	^t IPW	600	–	525	–	460	–	410	–	ps	
ACTIVATE to internal READ or WRITE delay	^t RCD	See Speed Bin Tables for ^t RCD								ns	
PRECHARGE command period	^t RP	See Speed Bin Tables for ^t RP								ns	
ACTIVATE-to-PRECHARGE command period	^t RAS	See Speed Bin Tables for ^t RAS								ns	
ACTIVATE-to-ACTIVATE or REF command period	^t RC	See Speed Bin Tables for ^t RC								ns	
ACTIVATE-to-ACTIVATE command period to different bank groups for 1/2KB page size	^t RRD_S (1/2KB)	MIN = greater of 4CK or 5ns		MIN = greater of 4CK or 4.2ns		MIN = greater of 4CK or 3.7ns		MIN = greater of 4CK or 3.3ns		CK	
ACTIVATE-to-ACTIVATE command period to different bank groups for 1KB page size	^t RRD_S (1KB)	MIN = greater of 4CK or 5ns		MIN = greater of 4CK or 4.2ns		MIN = greater of 4CK or 3.7ns		MIN = greater of 4CK or 3.3ns		CK	
ACTIVATE-to-ACTIVATE command period to different bank groups for 2KB page size	^t RRD_S (2KB)	MIN = greater of 4CK or 6ns		MIN = greater of 4CK or 5.3ns		MIN = greater of 4CK or 5.3ns		MIN = greater of 4CK or 5.3ns		CK	
ACTIVATE-to-ACTIVATE command period to same bank groups for 1/2KB page size	^t RRD_L (1/2KB)	MIN = greater of 4CK or 6ns		MIN = greater of 4CK or 5.3ns		MIN = greater of 4CK or 5.3ns		MIN = greater of 4CK or 4.9ns		CK	
ACTIVATE-to-ACTIVATE command period to same bank groups for 1KB page size	^t RRD_L (1KB)	MIN = greater of 4CK or 6ns		MIN = greater of 4CK or 5.3ns		MIN = greater of 4CK or 5.3ns		MIN = greater of 4CK or 4.9ns		CK	
ACTIVATE-to-ACTIVATE command period to same bank groups for 2KB page size	^t RRD_L (2KB)	MIN = greater of 4CK or 7.5ns		MIN = greater of 4CK or 6.4ns		MIN = greater of 4CK or 6.4ns		MIN = greater of 4CK or 6.4ns		CK	
Four ACTIVATE windows for 1/2KB page size	^t FAW (1/2KB)	MIN = greater of 16CK or 20ns		MIN = greater of 16CK or 17ns		MIN = greater of 16CK or 15ns		MIN = greater of 16CK or 13ns		ns	

Memory Timing 5

- From the Command and Address Input Levels table
- From the DQ Input Receiver Specifications table
- From the Reset and Initialization description
- From the Speed Bins and Operating Conditions table
- See next slide for data sheet extracts

The screenshot shows the 'Memory Timing' tab of a configuration tool. It displays a list of timing parameters for a memory device, categorized into three sections: 'Parameters dependent on Speed Bin', 'Parameters dependent on Speed Bin, Operating Frequency, and Page Size', and 'Parameters dependent on Density and Temperature'. Several parameters are highlighted with colored boxes: tIS (base) AC level (100 mV), tIH (base) DC level (75 mV), tdiVW_dj (0.1 cycles), VdiVW_total (136 mV), tINIT (500 us), tRAS (32.0 ns), tRCD (12.5 ns), and tRP (12.5 ns).

Parameters dependent on Speed Bin		
Speed bin:	-2400	
tIS (base):	60	ps
tIS (base) AC level:	100	mV
tIH (base):	95	ps
tIH (base) DC level:	75	mV
tdiVW_dj:	0.1	cycles
VdiVW_total:	136	mV
tDQSQ:	66	ps
tQH:	0.38	cycles
tDQSCK:	165	ps
tDQSS:	0.27	cycles
tQSH:	0.38	cycles
tDSH:	0.18	cycles
tDSS:	0.18	cycles
tWLS:	108.0	ps
tWLH:	108.0	ps
tINIT:	500	us
tMRD:	8	cycles
tRAS:	32.0	ns
tRCD:	12.5	ns
tRP:	12.5	ns
tWR:	15.0	ns

Parameters dependent on Speed Bin, Operating Frequency, and Page Size		
Update the following as you change the operating frequency, even if the device speed bin has not changed.		
tRRD_S:	7	cycles
tRRD_L:	8	cycles
tFAW:	30.0	ns
tCCD_S:	4	cycles
tCCD_L:	6	cycles
tWTR_S:	3	cycles
tWTR_L:	9	cycles

Parameters dependent on Density and Temperature		
Update the following as you change the physical memory device density. Incorrect values can cause data corruption.		
tRFC:	160.0	ns
tREFI:	7.8	us

Memory Timing 6

Extracts from a Micron Memory DDR4 Datasheet

Table 80: Command and Address Input Levels: DDR4-1600 Through DDR4-2400

Parameter	Symbol	Min	Max	Unit	Note
AC input high voltage	$V_{IH(AC)}$	$V_{REF} + 100$	V_{DD5}	mV	1, 2, 3
DC input high voltage	$V_{IH(DC)}$	$V_{REF} + 75$	V_{DD}	mV	1, 2
DC input low voltage	$V_{IL(DC)}$	V_{SS}	$V_{REF} - 75$	mV	1, 2
AC input low voltage	$V_{IL(AC)}$	V_{SS5}	$V_{REF} - 100$	mV	1, 2, 3
Reference voltage for CMD/ADDR inputs	$V_{REFCA(DC)}$	$0.49 \times V_{DD}$	$0.49 \times V_{DD}$	V	4

Table 82: DQ Input Receiver Specifications

Note 1 applies to the entire table

Parameter	Symbol	DDR4-1600, 1866, 2133		DDR4-2400		DDR4-2666, 3200		Unit	Notes
		Min	Max	Min	Max	Min	Max		
V_{IN} Rx mask input peak-to-peak	V_{diVW}	-	136 ¹	-	130 ¹	-	125	mV	2, 3
DQ Rx input timing window	T_{diVW}	-	0.2 ¹	-	0.2 ¹	-	0.22 ¹	UI	2, 3
DQ AC input swing peak-to-peak	$V_{IH(AC)}$	186	-	160	-	150	-	mV	4, 5
DQ input pulse width	T_{diPW}	0.58	-	0.58	-	0.58	-	UI	6
DOS-to-DO Rx mask offset	${}^1D_{OS2DO}$	-0.17	0.17	-0.17	0.17	-0.22	0.22	UI	7

Power-Up and Initialization Sequence

- After $RESET_n$ is de-asserted, wait for another 500 μ s until CKE becomes active.

Table 139: DDR4-2400 Speed Bins and Operating Conditions

DDR4-2400 Speed Bin			-083F		-083E		-083		Unit
CL-nRCD-nRP			15-15-15		16-16-16		17-17-17		
Parameter	Symbol	Min	Max	Min	Max	Min	Max	Min	Max
Internal READ command to first data	1AA	12.5	18.00	13.32	18.00	14.16	18.00	14.16	18.00
Internal READ command to first data with read DBI enabled	1AA_DBI	${}^1AA(MIN) + 3nCK$	-						
ACTIVATE to internal READ or WRITE delay time	1RCD	12.5	-	13.32	-	14.16	-	14.16	-
PRECHARGE command period	1RP	12.5	-	13.32	-	14.16	-	14.16	-
ACTIVATE-to-PRECHARGE command period	1RAS	32	$9 \times {}^1REFI$						
ACTIVATE-to-ACTIVATE or REFRESH command period	1RC	${}^1RAS + {}^1RP$	-						
READ: nonDBI	READ: DBI	WRITE	Symbol	Min	Max	Min	Max	Min	Max
CL = 9	CL = 11	CWL = 9	1CK	1.5	1.6	1.5	1.6	Reserved	
CL = 10	CL = 12	CWL = 9	1CK	1.5	1.6	Reserved		1.5	1.6
CL = 10	CL = 12	CWL = 9, 11	1CK	Reserved		Reserved		Reserved	
CL = 11	CL = 13	CWL = 9, 11	1CK	Reserved		1.25	<1.5	1.25	<1.5
CL = 12	CL = 14	CWL = 9, 11	1CK	1.25	<1.5	1.25	<1.5	1.25	<1.5

Memory Timing 7

- Check tRFC is correct for the capacity of the DDR4 memory device
 - Use the tRFC1 value from the DDR4 datasheet

Refresh Timing				
REFRESH-to-ACTIVATE or REFRESH command period (all bank groups)	4Gb	tRFC1	MIN = 260	ns
		tRFC2	MIN = 160	ns
		tRFC4	MIN = 110	ns
	8Gb	tRFC1	MIN = 350	ns
		tRFC2	MIN = 260	ns
		tRFC4	MIN = 160	ns
	16Gb	tRFC1	MIN = 550	ns
		tRFC2	MIN = 405	ns
		tRFC4	MIN = 250	ns
Average periodic re-fresh interval	0°C ≤ T _C ≤ 85°C	tREFI	MIN = N/A; MAX = 7.8	μs
	85°C < T _C ≤ 95°C	tREFI	MIN = N/A; MAX = 3.9	μs

- Using the incorrect value can cause bit errors during memory accesses

Memory Timing 8

- ◀ Some timing parameters are in units of UI or U_d
 - UI/U_d is defined as the Unit Interval
 - Jedec specification formula : $UI = \text{minimum } [t_{CK}(\text{avg})/2]$
 - For the DDR4 IP parameters, set $UI = t_{CK}/2$

Table 143: Electrical Characteristics and AC Timing Parameters (Continued)

Parameter	Symbol	DDR4-1600		DDR4-1866		DDR4-2133		DDR4-2400		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
DQ Output Timing										
DQS_t, DQS_c to DQ skew, per group, per access	t _{DQSQ}	–	0.16	–	0.16	–	0.16	–	0.17	U _d
DQ output hold time from DQS_t, DQS_c	t _{QH}	0.76	–	0.76	–	0.76	–	0.74	–	U _d